Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/697,408	AKASHE ET AL.	
Examiner	Art Unit	
Anthony Weier	1761	

	SEAR	CHED	
Class	Subclass	Date	Examiner
426	656, 634, 574	1/9/2006	AW
		T.	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Search	1/9/2006	AW		